



**PRODUCT BULLETIN # 20482**

Generic Copy

**Issue Date:** 28-May-2014

**TITLE:** NCP551, NCV551 DATASHEET SPECIFICATION UPDATE

**PROPOSED FIRST SHIP DATE:** 28-Aug-2014

**AFFECTED CHANGE CATEGORY(S):** Datasheet

**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact your local ON Semiconductor sales office or <Bett.Lofts@onsemi.com>

**NOTIFICATION TYPE:**

ON Semiconductor considers this change approved unless specific conditions of acceptance are provided in writing. To do so, contact <quality@onsemi.com>.

**DESCRIPTION AND PURPOSE:**

Modification is made on page 3 in the ELECTRICAL CHARACTERISTICS table of the NCP551/D datasheet, Quiescent Current Test Vin condition change. The updated Vin Condition of IQ test parameter does not affect the device design, performance and application

See below the updated value highlighted in Red font.

FROM:

Quiescent Current (Enable Input = 0 V) (Enable Input = $V_{in}$ , $I_{out} = 1.0 \text{ mA}$ to $I_{Q(nom.)}$ )	$I_Q$	-	0.1	1.0	$\mu\text{A}$
		-	4.0	8.0	

TO:

Quiescent Current (Enable Input = 0 V) (Enable Input = $V_{in}$ , $I_{out} = 1.0 \text{ mA}$ to $I_{Q(nom.)}$ )	$I_Q$	-	0.1	1.0	$\mu\text{A}$
1.4V-2.0V ( $V_{in}=4.0V$ )		-	4.0	8.0	
2.1V-3.0V ( $V_{in}=5.0V$ )		-			
3.1V-4.0V ( $V_{in}=6.0V$ )		-			
4.1V-5.0V ( $V_{in}=8.0V$ )		-			

Purpose of change: Previous conditions did not permit sufficient input voltage for proper testing of the part Quiescent Current parameter.



**PRODUCT BULLETIN #20482**

**List of affected General Parts:**

NCV551SN14T1G  
NCV551SN15T1G  
NCV551SN18T1G  
NCV551SN25T1G  
NCV551SN27T1G  
NCV551SN28T1G  
NCV551SN30T1G  
NCV551SN31T1G  
NCV551SN32T1G  
NCV551SN33T1G  
NCV551SN50T1G  
NCP551SN15T1G  
NCP551SN18T1G  
NCP551SN25T1G  
NCP551SN27T1G  
NCP551SN28T1G  
NCP551SN29T1G  
NCP551SN30T1G  
NCP551SN31T1G  
NCP551SN32T1G  
NCP551SN33T1G  
NCP551SN50T1G